


<b>Search Notes</b>  	<b>Application/Control No.</b>  10522524	<b>Applicant(s)/Patent Under Reexamination</b>  MASUDA ET AL.
	<b>Examiner</b>  LI LIU	<b>Art Unit</b>  2613

SEARCHED			
Class	Subclass	Date	Examiner
398	1-7, 9-14, 17-20, 24, 25-29, 66, 140, 141, 158, 159, 165, 167.5, 183-189, 198	3/11/2008	LL
372	25, 26, 29.014, 29.016	3/11/2008	LL
359	237-239, 337.4	3/11/2008	LL

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB	2/27-3/12, 2008	LL
IEEE, GOOGLE	3/11-3/12, 2008	LL
PLUS	3/11/2008	LL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner